Prüfbericht-Nr.: *Test Report No.*:	**ULR:TC568819400000355F**	**Auftrags-Nr.:** *Order No.*:	1803381799	Seite 1 von 11 *Page 1 of 11*
Kunden-Referenz-Nr.: *Client Reference No.*:	633897	**Auftragsdatum:** *Order date*:	28/12/2018	
Auftraggeber: *Client*:	Saatvik Green Energy Private Limited,Village Dubli, Tehsil Barara, District Ambala, Haryana – 133001,India			
Prüfgegenstand: *Test item*:	Photovoltaic (PV) modules			
Bezeichnung / Typ-Nr.: *Identification / Type No.*:	SGE 325 -72P			
Auftrags-Inhalt: *Order content*:	Testing against PID resistivity			
Prüfgrundlage: *Test specification*:	Solar Photovoltaic Modules IEC TS 62804 – 1 :Test methods for the detection of potential-induced degradation – Part 1: Crystalline silicon with following severities - *Climatic conditions: 85°C and 85% RH* - *Duration: 288 hours*			

Wareneingangsdatum: *Date of receipt*:	31/12/2018
Prüfmuster-Nr.: *Test sample No.*:	Refer list of test samples
Prüfzeitraum: *Testing period*:	05/02/2019 – 26/02/2019
Ort der Prüfung: *Place of testing*:	Bangalore
Prüflaboratorium: *Testing laboratory*:	TUV Rheinland(India) Pvt. Ltd.,Bangalore,India
Prüfergebnis*: *Test result**:	Pass

Detaillierte Fotodokumentation
siehe Anlage zu diesem Bericht

Detailed photo documentation see appendix to this report

geprüft von / *tested by*:			**kontrolliert von** / *reviewed by*:		
24/07/2019	Prashanth GS/Sr.Engineer-PV Products		24/07/2019	K.Ganesh Kamath/Manager -PV Products	
Datum *Date*	**Name / Stellung** *Name / Position*	**Unterschrift** *Signature*	**Datum** *Date*	**Name / Stellung** *Name / Position*	**Unterschrift** *Signature*

Sonstiges / *Other*: none

Zustand des Prüfgegenstandes bei Anlieferung: Prüfmuster vollständig und unbeschädigt
Condition of the test item at delivery: *Test item complete and undamaged*

* Legende:	1 = sehr gut	2 = gut	3 = befriedigend	4 = ausreichend	5 = mangelhaft
	P(ass) = entspricht o.g. Prüfgrundlage(n)		F(ail) = entspricht nicht o.g. Prüfgrundlage(n)	N/A = nicht anwendbar	N/T = nicht getestet
Legend:	*1 = very good*	*2 = good*	*3 = satisfactory*	*4 = sufficient*	*5 = poor*
	P(ass) = passed a.m. test specification(s)		*F(ail) = failed a.m. test specification(s)*	*N/A = not applicable*	*N/T = not tested*

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Prüfbericht-Nr.: ULR:TC568819400000355F
Test Report No.:

Liste der verwendeten Prüfmittel
List of used test equipment

Prüfmittel *Test equipment*	**Prüfmittel-Nr. / ID-Nr.** *Equipment No. / ID-No.*	**Nächste Kalibrierung** *Next calibration*
Insulation Resistance Tester	50-2017-0272	14/02/2020
Insulation Resistance Tester	50-2017-0269	14/02/2020
Solar Simulator Pulsed	50-2010-0111	04/08/2019
Climatic chamber	50-2017-0283	13/12/2019
Reference Modules	50-2018-0297	15/08/2019
Infrared sensor	50-2010-0111B	01/09/2019

Produktbeschreibung
Product description

1	**Produktdetails** *Product details* SGE xxx-72P (300 -345 in steps of 1with 72 cells) xxx represents output power in Wp
2	**Verwendete Materialien** *Used materials* Refer constructional characteristics in the “List of test samples”
3	**Adresse(n) der Fertigungsstätte(n)** *Address(es) of the manufacturing site(s)* Saatvik Green Energy Private Limited, Village Dubli, Tehsil Barara, District Ambala, Haryana – 133001,India
4	**Zusammenfassung der Prüfergebnisse** *Summary of test results* "According to the enquiry of the manufacturer for a testing against PID resistivity shall be performed according to IEC TS 62804 with following severities – - Negative potential of the specified maximum system voltage between the shorted output terminals and the frame(ground), - 1500V DC - Climatic conditions: 85°C and 85% RH - Duration: 288 hours Before and after the PID test, Visual inspection, maximum power determination, Ground continuity and documentation by electroluminescence imaging shall be performed. In line with the international standard for PV module type approval testing EN IEC 61215, two modules will be tested. One additional module will be used as a reference sample. ***Pass Criteria:*** A module design shall be judged to have passed the PID test , if each test sample meets all the following criteria: • The degradation of maximum output power does not exceed 5%. • No evidence of a major visual defect (as defined in IEC 61215:2005) **All presented results are only valid for the exact tested module type and design (cell type, encapsulation material, glass type)**